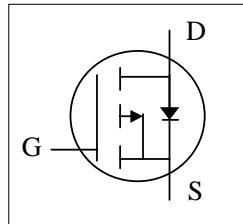




- ▼ Simple Drive Requirement
- ▼ 2.5V Gate Drive Capability
- ▼ Fast Switching Characteristic

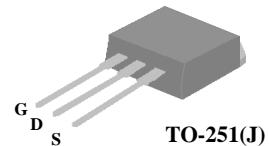
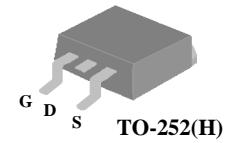


BV_{DSS}	-20V
$R_{DS(ON)}$	150mΩ
I_D	-10A

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, low on-resistance and cost-effectiveness.

This device is suited for low voltage and battery power applications.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-20	V
V_{GS}	Gate-Source Voltage	± 12	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V$	-10	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 4.5V$	-6.2	A
I_{DM}	Pulsed Drain Current ¹	-24	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	25	W
	Linear Derating Factor	0.01	W/ $^\circ C$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	5.0	$^\circ C/W$
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient (PCB mount) ³	62.5	$^\circ C/W$
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient	110	$^\circ C/W$



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Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=-250\mu\text{A}$	-20	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=-1\text{mA}$	-	-0.1	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-4.5\text{V}$, $I_D=-2.8\text{A}$	-	-	150	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}$, $I_D=-2.0\text{A}$	-	-	250	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=-250\mu\text{A}$	-0.5	-	-	V
g_f	Forward Transconductance	$V_{\text{DS}}=-5\text{V}$, $I_D=-2.8\text{A}$	-	4.4	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-20\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-1	μA
	Drain-Source Leakage Current ($T_j=125^\circ\text{C}$)	$V_{\text{DS}}=-16\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-250	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 12\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_D=-2.8\text{A}$	-	6	-	nC
Q_{gs}	Gate-Source Charge		-	1.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge		-	0.6	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time ²	$V_{\text{DS}}=-6\text{V}$ $I_D=-1\text{A}$	-	25	-	ns
t_r	Rise Time		-	60	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time		-	70	-	ns
t_f	Fall Time		$R_G=6\Omega$, $V_{\text{GS}}=-5\text{V}$	-	60	-
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$ $V_{\text{DS}}=-6\text{V}$ $f=1.0\text{MHz}$	-	300	-	pF
C_{oss}	Output Capacitance		-	180	-	pF
C_{rss}	Reverse Transfer Capacitance		-	60	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
I_s	Continuous Source Current (Body Diode)	$V_D=V_G=0\text{V}$, $V_S=-1.2\text{V}$	-	-	-10	A
I_{SM}	Pulsed Source Current (Body Diode) ¹		-	-	-24	A
V_{SD}	Forward On Voltage ²	$T_j=25^\circ\text{C}$, $I_s=-10\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	-1.2	V

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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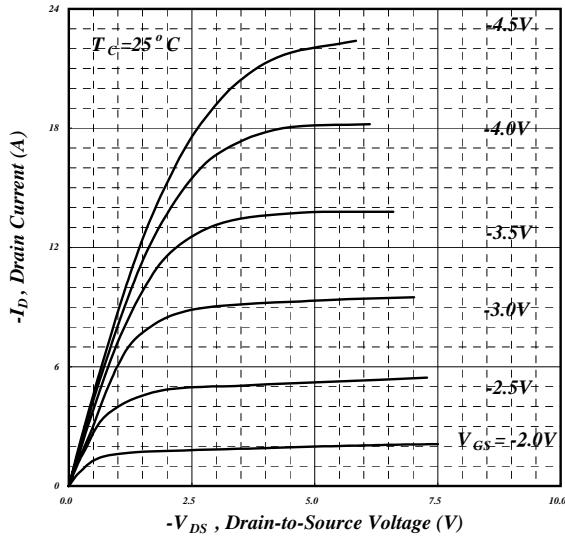


Fig 1. Typical Output Characteristics

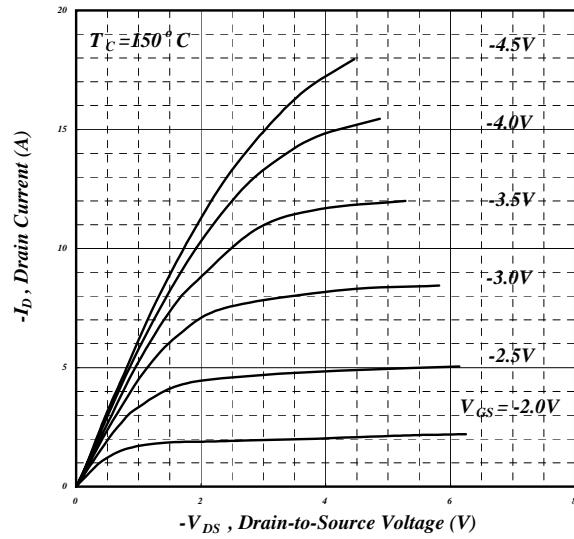


Fig 2. Typical Output Characteristics

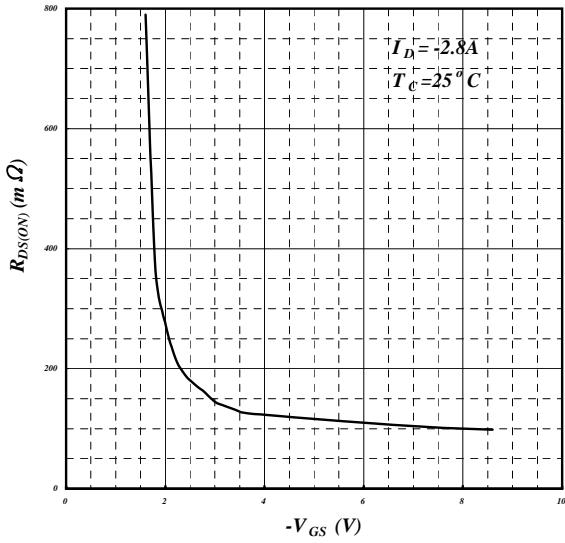


Fig 3. On-Resistance v.s. Gate Voltage

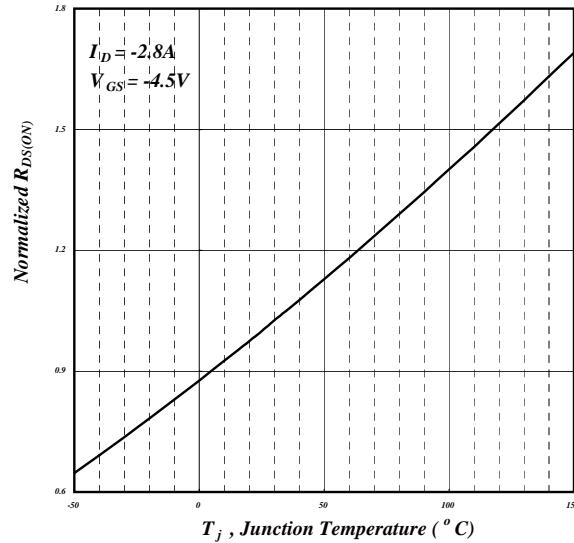
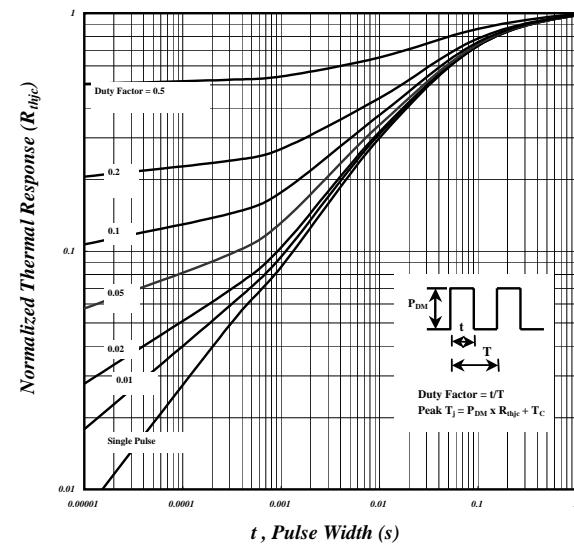
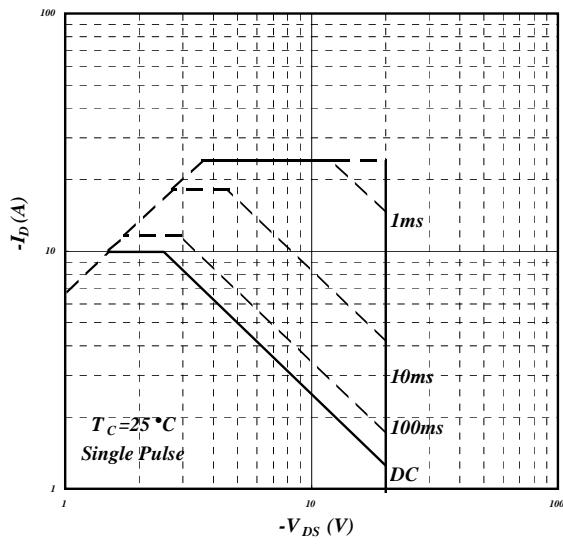
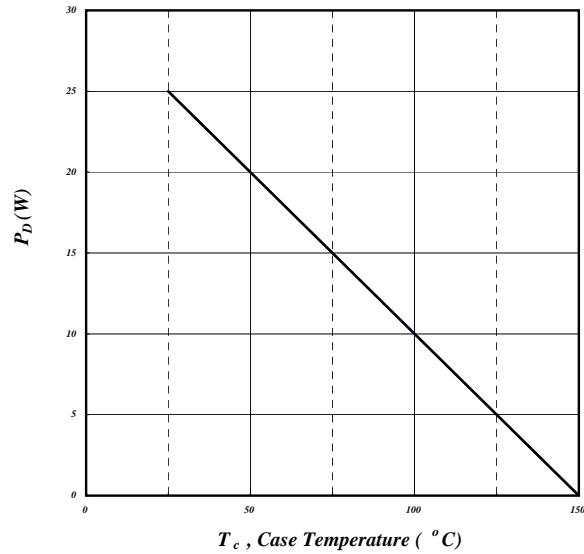
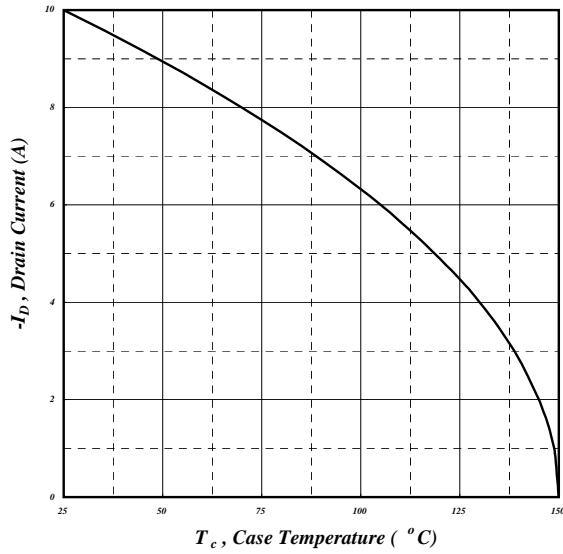


Fig 4. Normalized On-Resistance v.s. Junction Temperature



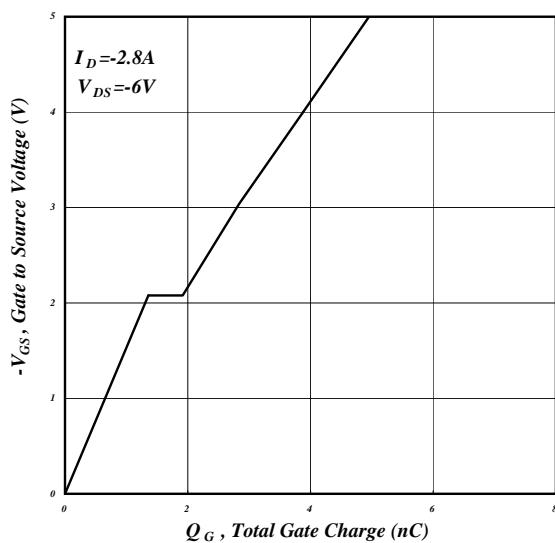


Fig 9. Gate Charge Characteristics

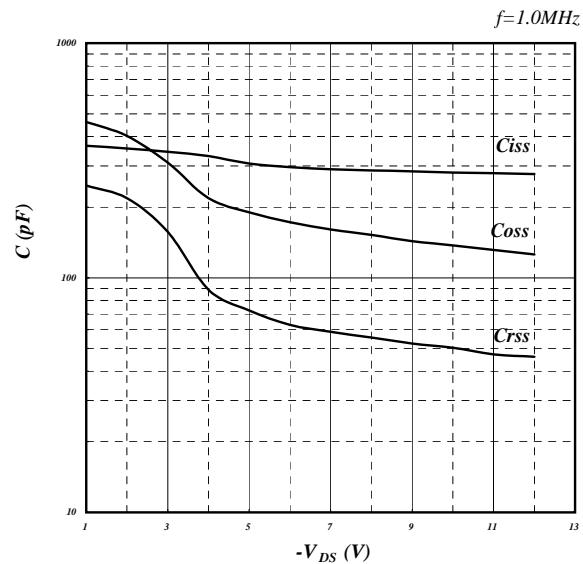


Fig 10. Typical Capacitance Characteristics

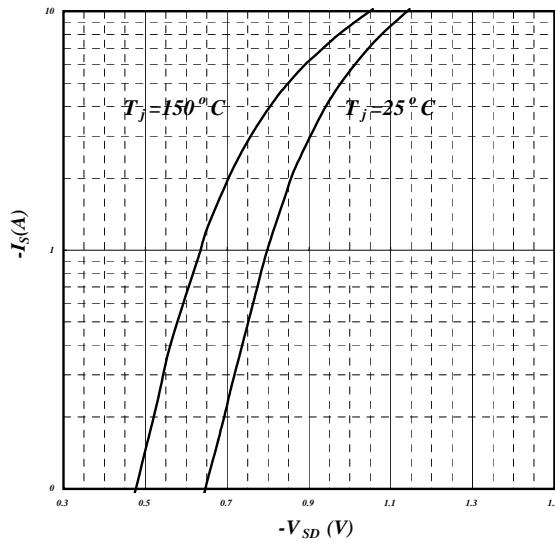


Fig 11. Forward Characteristic of Reverse Diode

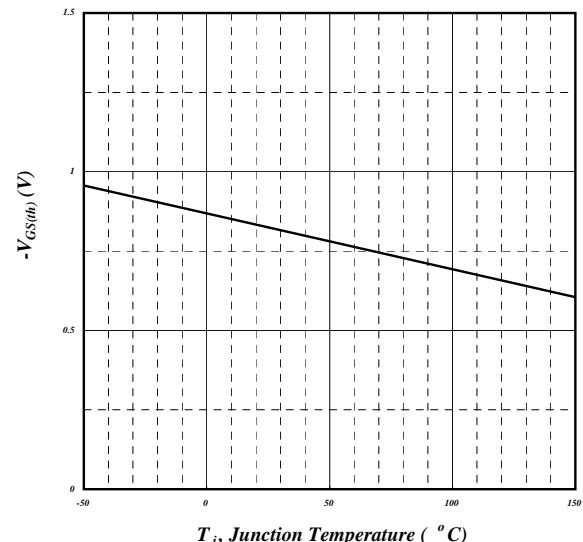


Fig 12. Gate Threshold Voltage v.s. Junction Temperature



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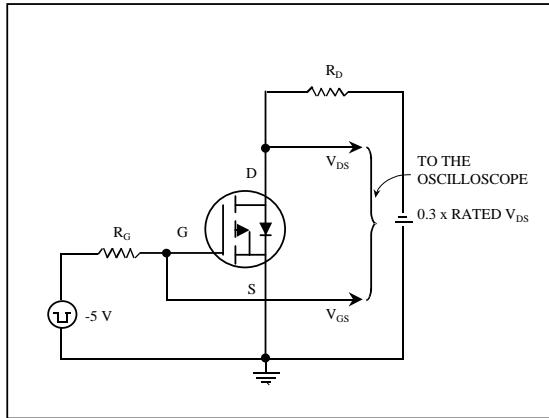


Fig 13. Switching Time Circuit

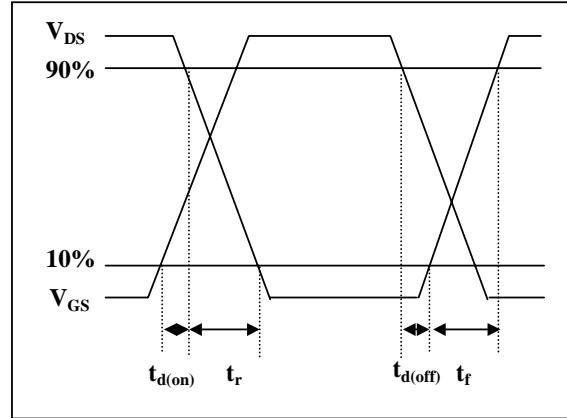


Fig 14. Switching Time Waveform

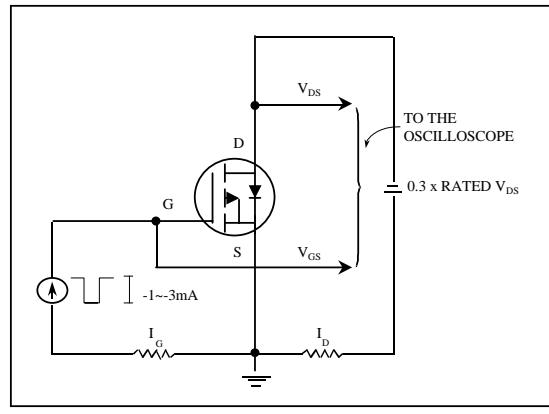


Fig 15. Gate Charge Circuit

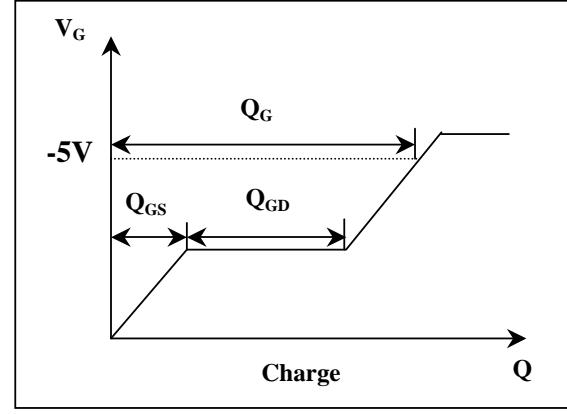


Fig 16. Gate Charge Waveform